



ITW

PATENT

Attorney Docket No. YOR920030276US1 (8728-633)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Daniel Worledge

Group No.: 2856

Serial No.: 10/688,630

Examiner: Robert R. Raevis

Filed: October 17, 2003

Date of mailing of "Notice of Allowance and  
Base Issue Fee Due" November 3, 2005

Confirmation No. 1945

For: ATOMIC FORCE MICROSCOPE AND METHOD FOR DETERMINING  
PROPERTIES OF A SAMPLE SURFACE USING AN ATOMIC FORCE  
MICROSCOPE

MAIL STOP ISSUE FEE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**TRANSMITTAL OF FORMAL DRAWINGS**

Attached please find one (1) sheets of formal drawings for the above-identified application.

Please charge any deficiency as well as any other fee(s) which may become due under 37 C.F.R. § 1.16 and/or 1.17 at any time during the pendency of this application, or credit any overpayment of such fee(s) to Deposit Account No. 50-0510/IBM. TWO (2) COPIES OF THIS SHEET ARE ENCLOSED.

SIGNATURE OF ATTORNEY

Frank V. DeRosa

Type or print name of attorney

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(Transmittal of Formal Drawings [5-2])